



**ALPHA & OMEGA**  
SEMICONDUCTOR



**AON4603**

Complementary Enhancement Mode Field Effect Transistor

### General Description

The AON4603 uses advanced trench technology to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications. Standard Product AON4603 is Pb-free (meets ROHS & Sony 259 specifications). AON4603L is a Green Product ordering option. AON4603 and AON4603L are electrically identical.

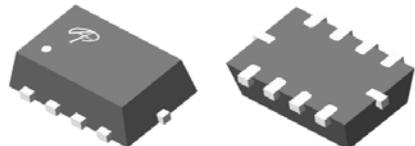
### Features

#### n-channel      p-channel

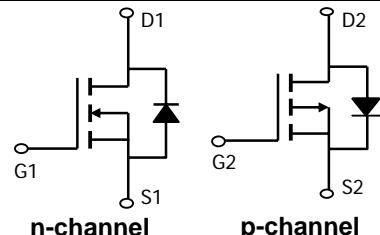
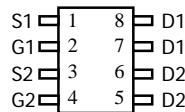
$V_{DS}$ (V) = 30V	-30V
$I_D$ = 4A	-3.6A
$R_{DS(ON)} < 75m\Omega$	< 100m $\Omega$
$R_{DS(ON)} < 115m\Omega$	< 180m $\Omega$

( $V_{GS} = \pm 10V$ )

( $V_{GS} = \pm 4.5V$ )



DFN2X3



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current <sup>A</sup>	$I_D$	4	-3.6	A
$T_A=70^\circ C$		3.2	-2.9	
Pulsed Drain Current <sup>B</sup>	$I_{DM}$	12	-12	
Power Dissipation	$P_D$	1.9	2.1	W
$T_A=70^\circ C$		1.2	1.3	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	°C

### Thermal Characteristics: n-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	54	65	°C/W
Steady-State		102	125	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	58	70	°C/W

### Thermal Characteristics: p-channel

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{\theta JA}$	50	60	°C/W
Steady-State		85	110	°C/W
Maximum Junction-to-Lead <sup>C</sup>	$R_{\theta JL}$	41	50	°C/W

**N-Channel Electrical Characteristics ( $T_j=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$ $T_j=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.9	3	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	12			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=4\text{A}$ $T_j=125^\circ\text{C}$		55	75	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=2\text{A}$		78		
				95	115	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=4\text{A}$		5.4		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}$		0.82	1	V
$I_S$	Maximum Body-Diode Continuous Current				2.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		200	260	pF
$C_{oss}$	Output Capacitance			40		pF
$C_{rss}$	Reverse Transfer Capacitance			20		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		2.3	3.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=4\text{A}$		6.5	8.5	nC
$Q_g(4.5\text{V})$	Total Gate Charge			3.1	4	nC
$Q_{gs}$	Gate Source Charge			1.2		nC
$Q_{gd}$	Gate Drain Charge			1.6		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=3.75\Omega, R_{\text{GEN}}=3\Omega$		3.3		ns
$t_r$	Turn-On Rise Time			2.5		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			13.2		ns
$t_f$	Turn-Off Fall Time			1.7		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		9.4	12	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		3.5		nC

A: The value of  $R_{\text{0JA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

The value in any given application depends on the user's specific board design. The current rating is based on the  $t \leq 10\text{s}$  thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The  $R_{\text{0JA}}$  is the sum of the thermal impedance from junction to lead  $R_{\text{0JL}}$  and lead to ambient.

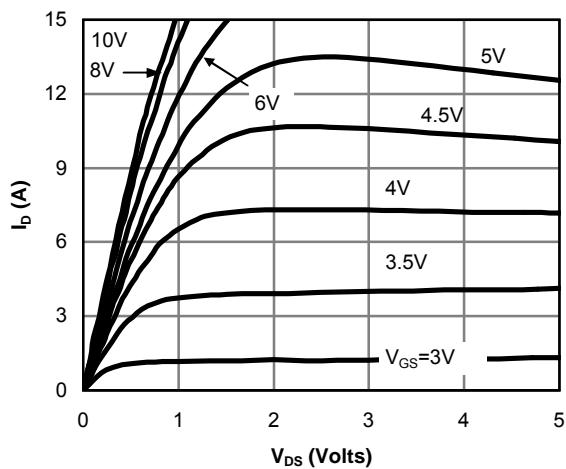
D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 $\mu\text{s}$  pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The SOA curve provides a single pulse rating.

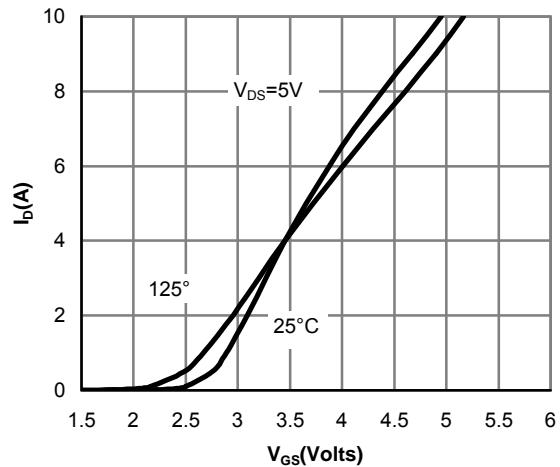
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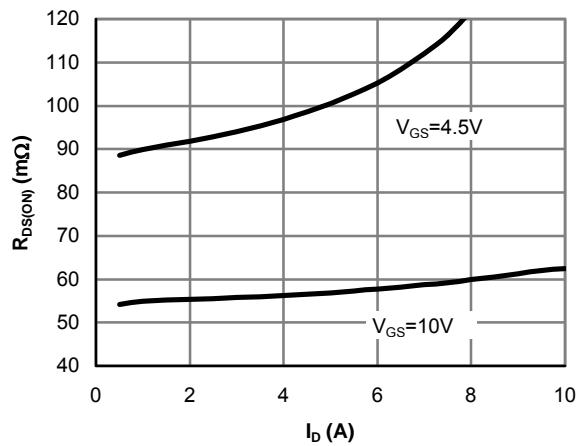
### N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$ unless otherwise noted)



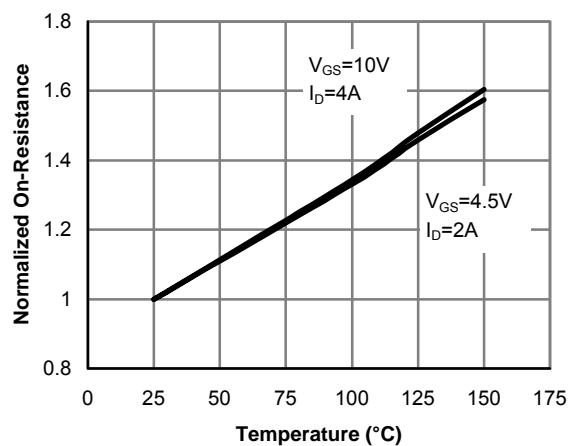
**Fig 1: On-Region Characteristics**



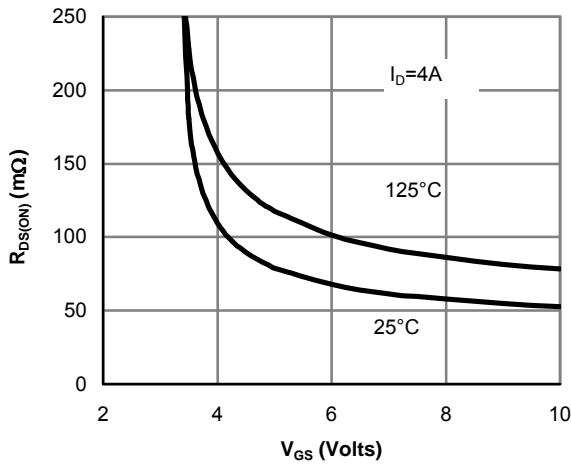
**Figure 2: Transfer Characteristics**



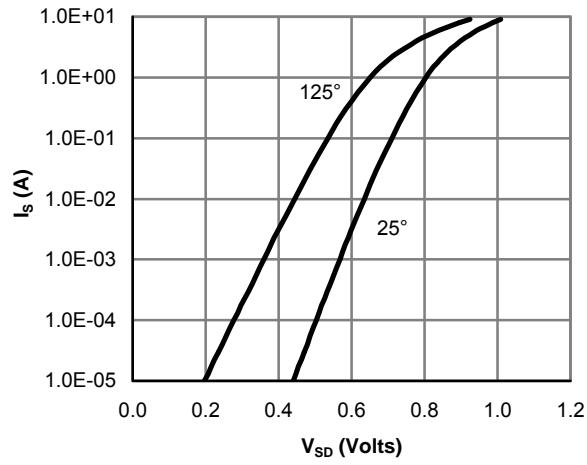
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**



**Figure 5: On-Resistance vs. Gate-Source Voltage**



**Figure 6: Body-Diode Characteristics**

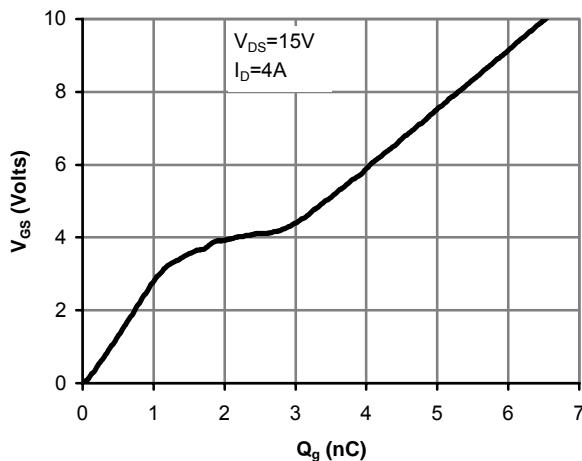
N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Figure 7: Gate-Charge Characteristics

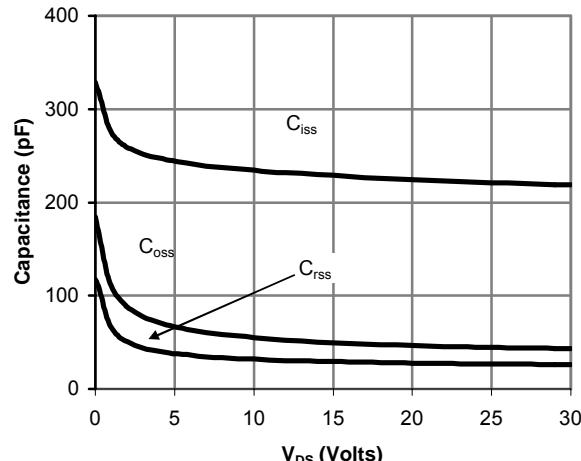


Figure 8: Capacitance Characteristics

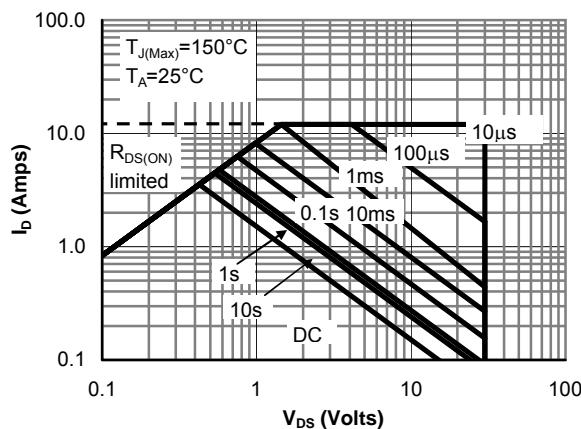


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

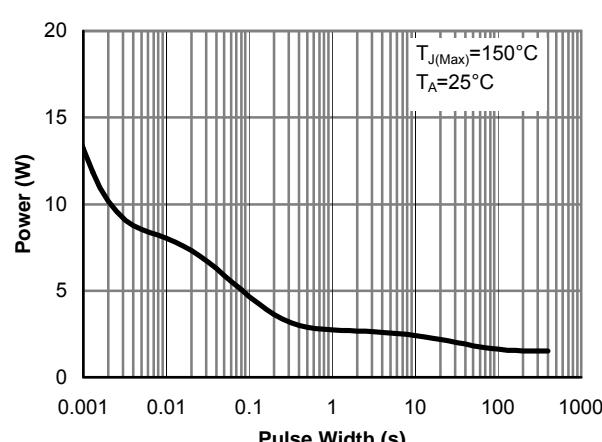


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

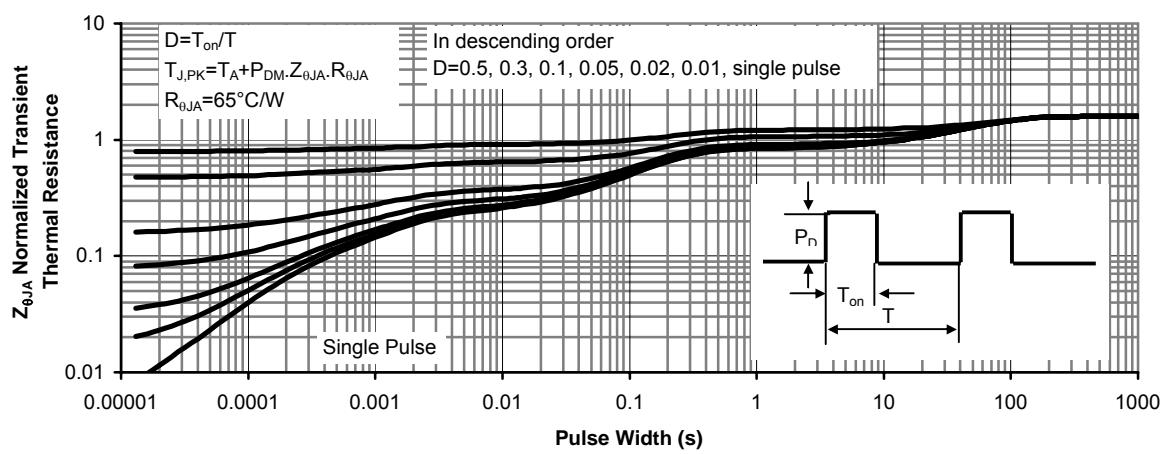


Figure 11: Normalized Maximum Transient Thermal Impedance

**P-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-30			V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-1	-2	-3	V
$I_{\text{D(ON)}}$	On state drain current	$V_{GS}=-10\text{V}, V_{DS}=-5\text{V}$	-12			A
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}, I_D=-3.6\text{A}$ $T_J=125^\circ\text{C}$		81 115	100	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$		136	180	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-3.6\text{A}$		4.8		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=-1\text{A}, V_{GS}=0\text{V}$		-0.82	-1	V
$I_s$	Maximum Body-Diode Continuous Current				-2.5	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		260	340	pF
$C_{\text{oss}}$	Output Capacitance			55		pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			44		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		4.3	6.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10)$	Total Gate Charge(10V)	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-3.6\text{A}$		5.8	7	nC
$Q_g(4.5)$	Total Gate Charge(4.5V)			3	4	nC
$Q_{\text{gs}}$	Gate Source Charge			0.78		nC
$Q_{\text{gd}}$	Gate Drain Charge			1.6		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=4.2\Omega, R_{\text{GEN}}=3\Omega$		7		ns
$t_r$	Turn-On Rise Time			6		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			15		ns
$t_f$	Turn-Off Fall Time			7.5		ns
$t_{\text{rr}}$	Body Diode Reverse Recovery Time	$I_F=-3.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		12.5	15	ns
$Q_{\text{rr}}$	Body Diode Reverse Recovery Charge	$I_F=-3.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		5.5		nC

A: The value of  $R_{\text{0JA}}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: P-CHANNEL

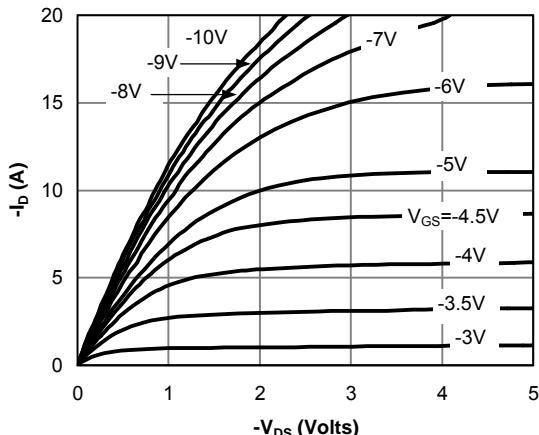


Fig 1: On-Region Characteristics

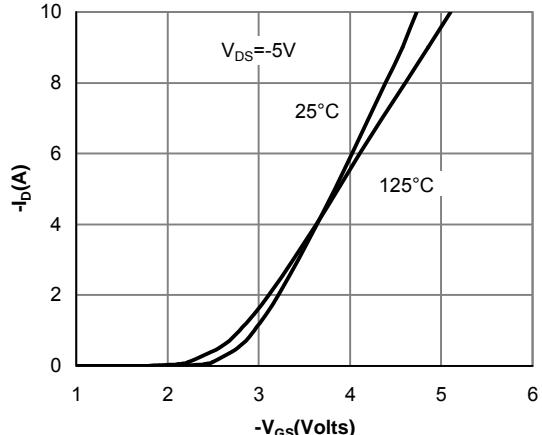


Figure 2: Transfer Characteristics

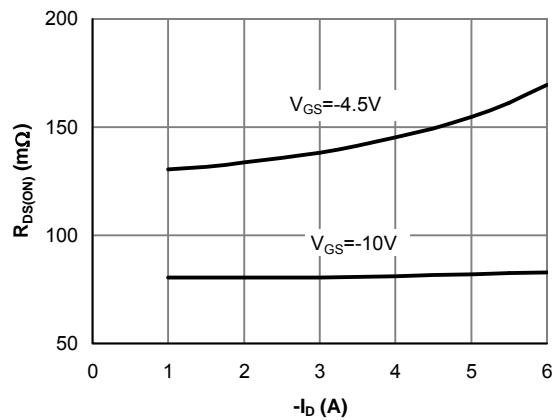


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

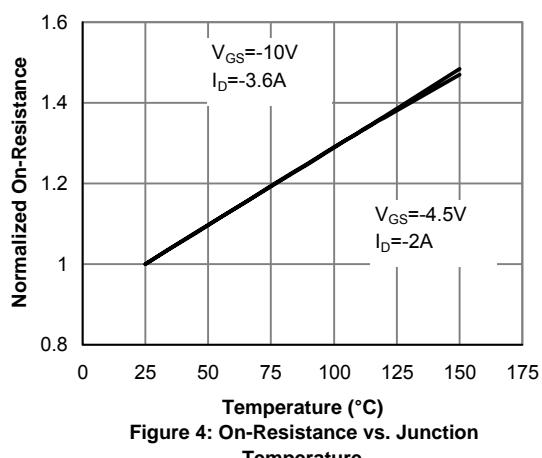


Figure 4: On-Resistance vs. Junction Temperature

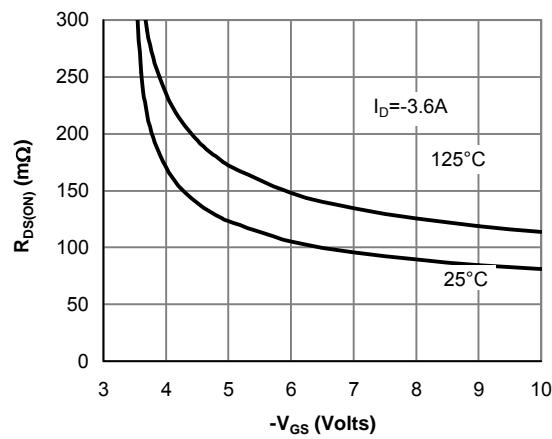


Figure 5: On-Resistance vs. Gate-Source Voltage

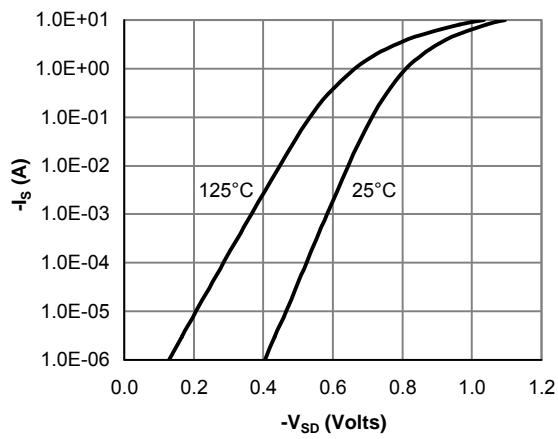


Figure 6: Body-Diode Characteristics

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